







TUSB211A

ZHCST15 - SEPTEMBER 2023

TUSB211A USB 2.0 480Mbps 高速信号调节器

1 特性

- 宽电源电压范围: 2.3V 至 6.5V
- 超低 USB 断开和关断功耗
- 可提供 USB 2.0 高速信号调节
- 兼容 USB 2.0、On-The-Go (OTG) 2.0 和电池充电 (BC) 1.2
- 支持低速、全速和高速信号传输
- 主机或器件无关
- 支持长达 5m 的电缆
 - 通过外部下拉电阻器值实现四种可选的信号 EQ (边沿升压与直流升压)设置
- 支持长达 10m 的电缆和两台 TUSB211A 器件
- 可扩展解决方案 器件可通过菊花链连接用于高损
- 与 TUSB211/212/214/216/217A 引脚兼容 (3.3V)

2 应用

- 笔记本电脑、台式机或扩展坞
- 便携式电子产品
- 平板电脑
- 手机
- 电视
- 有源电缆、电缆扩展器、背板

3 说明

TUSB211A 是第三代 USB 2.0 高速信号调节器,旨在 补偿传输通道中的交流损失(由于电容性负载)和直流 损失(由于电阻性负载)。

TUSB211A 采用了专利设计,可通过边缘加速器来对 USB 2.0 高速信号的传输边缘进行加速,并通过直流升 压功能来提高静态电平。

此外, TUSB211A 还具有预均衡功能,可补偿较长电 缆应用中的码间串扰 (ISI) 抖动。USB 低速和全速信号 特征不受 TUSB211A 的影响。

TUSB211A 可在不改变数据包计时或不增加传播延迟 的情况下提高信号质量。

TUSB211A 可使用长达 5 米的线缆帮助系统通过 USB 2.0 高速近端眼图合规性测试。

TUSB211A 与 USB On-The-Go (OTG) 和电池充电 (BC) 协议兼容。

器件信息

器件型号	B件型号 封装 ⁽¹⁾ OP TEMP (T _A) °C		封装尺寸(标称值)		
TUSB211A	RWB	0至70	1.0		
TUSB211AI	(X2QFN, 12)	-40 至 85	1.6mm x 1.6mm		

- 如需了解所有可用封装,请参阅数据表末尾的可订购产品附
- 封装尺寸(长x宽)为标称值,不包括引脚。

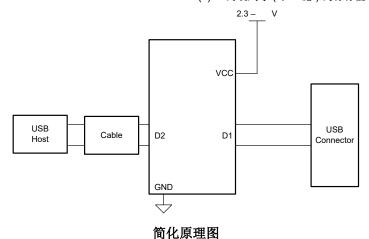




Table of Contents

1 特性	1 7.2 Functional Block Diagram	7
2 应用	70F / D : /:	<mark>7</mark>
3 说明	7 4 Danie - Francisco - I Martin	<mark>7</mark>
4 Revision History	0 4	9
5 Pin Configuration and Functions	0 4 4!: 4: 4:	9
6 Specifications	0 0 T : 1 A 1: 4:	9
6.1 Absolute Maximum Ratings		15
6.2 ESD Ratings	0 4 1	15
6.3 Recommended Operating Conditions	0 Davida a and Da access and add and Occasion and	17
6.4 Thermal Information		17
6.5 Electrical Characteristics		17
6.6 Switching Characteristics		17
6.7 Timing Requirements		17
6.8 Typical Characteristics		17
7 Detailed Description		
7.1 Overview		17

4 Revision History

DATE	REVISION	NOTES
September 2023	*	Initial Release

Product Folder Links: TUSB211A



5 Pin Configuration and Functions

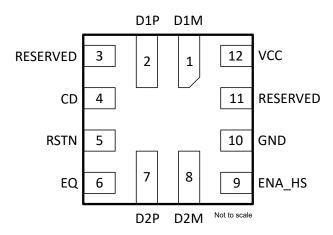


图 5-1. TUSB211A RWB 12-Pin X2QFN (Top View)

表 5-1. Pin Functions

PIN		TYPE(1)	INTERNAL	DESCRIPTION		
NAME NO.		ITPE	PULLUP/PULLDOWN	DESCRIPTION		
EQ	6	I	N/A	USB High-speed EQ select via external pull down resistor. Both edge boost and DC boost are controlled by a single pin. Sampled upon power up. Does not recognize real time adjustments. Auto selects EQ LEVEL = 3 when left floating.		
RESERVED	11	I	500 kΩ PU	Reserved pin for TI test purposes. Leave floating or connect external capacitor to GND for normal operation.		
ENA_HS	9	I/O	N/A	After reset: Output signal ENA_HS. Flag indicating that channel is in High-speed mode. Asserted upon: 1. Detection of USB-IF High-speed test fixture from an unconnected state followed by transmission of USB TEST_PACKET pattern. 2. Squelch detection following USB reset with a successful HS handshake [HS handshake is declared to be successful after single chirp J chirp K pair where each chirp is within 18 µs - 128 µs].		
D2P	7	I/O	N/A	USB High-speed positive port.		
D2M	8	I/O	N/A	USB High-speed negative port.		
GND	10	Р	N/A	Ground		
D1M	1	I/O	N/A	USB High-speed negative port.		
D1P	2	I/O	N/A	USB High-speed positive port.		
RESERVED	3	I/O	500 kΩ PU 1.8 MΩ PD	Reserved pin for TI test purposes. Leave floating for normal operation.		
VCC	12	Р	N/A	Supply power		
RSTN	5	I	500 kΩ PU 1.8 MΩ PD	Device disable/enable. Low - Device is at reset and in shutdown, and High - Normal operation. Recommend 0.1-µF external capacitor to GND to ensure clean power on reset if not driven. If the pin is driven, it must be held low until the supply voltage for the device reaches within specifications.		
CD	4	0	When RSTN asserted there is a 500 kΩ PD	After reset: Output CD. Flag indicating that a USB device is attached (connection detected). Asserted from an unconnected state upon detection of DP or DM pull-up resistor. De-asserted upon detection of disconnect.		

(1) I = input, O = output, P = power



6 Specifications

6.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
Supply voltage range	VCC	- 0.3	7	V
Voltage range USB data	DxP, DxM	- 0.3	5.5	V
Voltage range on EQ pin	EQ	-0.3	1.98	V
Voltage range other pins	RSTN	-0.3	5.5	V
Storage temperature, T _{stg}		- 65	150	°C
Maximum junction temperature, T	Maximum junction temperature, T _{J (max)}		125	°C

⁽¹⁾ Operation outside the *Absolute Maximum Rating* may cause permanent device damage. *Absolute Maximum Rating* do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Condition*. If used outside the *Recommended Operating Condition* but within the *Absolute Maximum Rating*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽²⁾	±2000	V
V _(ESD)	Lieotrostatic discriarge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽³⁾	±750	v

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	2.3	5	6.5	V
-	Operating free-air temperature (TUSB211A)	0		70	°C
T _A	Operating free-air temperature (TUSB211AI)	- 40		85	°C
т.	Junction temperature (TUSB211A)			85	°C
TJ	Junction temperature (TUSB211AI)			105	°C
DxP, DxM	Voltage range USB data	0		3.6	V
EQ	Voltage range EQ pin	0		1.98	V
DIGITAL	Voltage range other pins (RSTN)	0		3.6	V

6.4 Thermal Information

	THERMAL METRIC (1)	RWB (X2QFN)	UNIT
	I HERMAL METRIC (7)	12 PINS	UNII
R _{0 JA}	Junction-to-ambient thermal resistance	137.4	°C/W
R ₀ JC(top)	Junction-to-case (top) thermal resistance	62	°C/W
R _{0 JB}	Junction-to-board thermal resistance	67.2	°C/W
ψJT	Junction-to-top characterization parameter	1.9	°C/W
∮ ЈВ	Junction-to-board characterization parameter	67.3	°C/W
R ₀ JC(bot)	Junction-to-case (bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

6.5 Electrical Characteristics

Over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP (1)	MAX	UNIT
POWER						
I _{ACTIVE_HS}	High Speed Active Current	USB channel = HS mode. 480 Mbps traffic. V _{CC} supply stable, with EQ = Max		22	36	mA
I _{IDLE_HS}	High Speed Idle Current	USB channel = HS mode, no traffic. V _{CC} supply stable, EQ = Max		22	36	mA
I _{HS_SUSPEND}	High Speed Suspend Current	USB channel = HS Suspend mode. V_{CC} supply stable		0.75	1.4	mA
I _{FS}	Full-Speed Current	USB channel = FS mode, 12 Mbps traffic, V _{cc} supply stable		0.75	1.4	mA
I _{DISCONN}	Disconnect Power	Host side application. No device attachment.		0.80	1.4	mA
I _{SHUTDN}	Shutdown Power	RSTN driven low, V _{CC} supply stable		60	115	μA
CONTROL PIN I	EAKAGE	<u> </u>				
I _{LKG_FS}	Pin failsafe leakage current for RSTN	V _{CC} = 0 V, pin at V _{IH, max}		10	15	μA
INPUT RSTN		,			L	
V _{IH}	High level input voltage		1.5		3.6	V
V _{IL}	Low-level input voltage		0		0.5	V
I _{IH}	High level input current	V _{IH} = 3.6 V, R _{PU} enabled			±15	μΑ
I _{IL}	Low level input current	V _{IL} = 0V, R _{PU} enabled			±20	μΑ
INPUT EQ		1			J	
R _{EQ_LVL0}	External pulldown resistor for EQ Level 0				160	Ω
R _{EQ_LVL1}	External pulldown resistor for EQ Level 1		1.5	1.8	2	kΩ
R _{EQ_LVL2}	External pulldown resistor for EQ Level 2		3.4	3.6	3.96	$\mathbf{k}\Omega$
R _{EQ_LVL3}	External pulldown resistor for EQ Level 3 to remove upper limit for resistor value, can be left open		7.5			k Ω
OUTPUTS CD, E	ENA_HS					
V _{OH}	High level output voltage for CD and ENA_HS	I _O = -50 μA, VCC >= 3.0 V	2.5			V
V _{OH}	High level output voltage for CD	I _O = -25 μA, VCC = 2.3 V	1.7			V
V _{OH}	High level output voltage for ENA_HS	I _O = -25 μA, VCC = 2.3 V	1.8			V
V _{OL}	Low level output voltage for CD and ENA_HS	Ι _Ο = 50 μΑ			0.3	V
DxP, DxM	·					
C _{IO_DXX}	Capacitance to GND	Measured with VNA at 240 MHz, V _{CC} supply stable, Redriver off		2.5		pF

⁽¹⁾ All typical values are at V_{CC} = 5 V, and T_A = 25°C.

6.6 Switching Characteristics

Over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP (1)	MAX	UNIT
DxP, DxM USB Signals						
F _{BR_DXX}	Bit Rate	USB channel = HS mode. 480 Mbps traffic. V _{CC} supply stable			480	Mbps
t _{R/F_DXX}	Rise/Fall time		100			ps

⁽¹⁾ All typical values are at V_{CC} = 5 V, and T_A = 25°C.

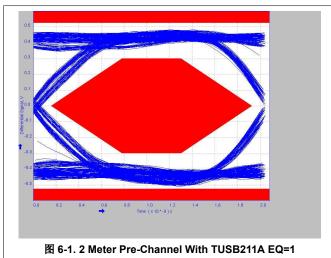


6.7 Timing Requirements

		MIN	NOM MAX	UNIT			
POWER UP	POWER UP TIMING						
T _{RSTN_PW}	Minimum width to detect a valid RSTN signal assert when the pin is actively driven low	100		μs			
T _{STABLE}	VCC must be stable before RSTN de-assertion	300		μs			
T _{READY}	Maximum time needed for the device to be ready after RSTN is deasserted.		500	μs			
T _{RAMP}	V _{CC} ramp time		100	ms			
T _{RAMP}	V _{CC} ramp time	0.2		ms			

6.8 Typical Characteristics

The typical characteristics shown in this section apply to near-end eye measurements taken at nominal conditions. The eyes are measured with various pre-channel cable lengths applied at the input or post-channel cable lengths applied at the output of the TUSB211A as indicated.



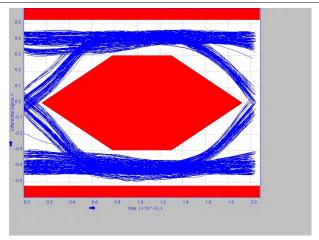
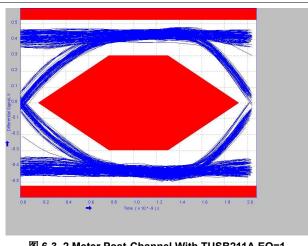


图 6-2. 5 Meter Pre-Channel With TUSB211A EQ=2





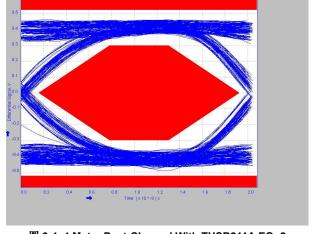


图 6-4. 4 Meter Post-Channel With TUSB211A EQ=2

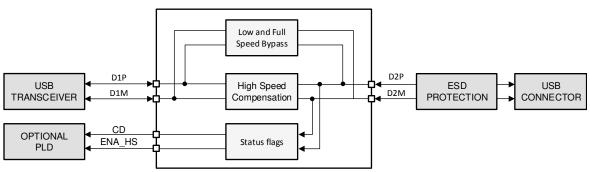
7 Detailed Description

7.1 Overview

The TUSB211A is a USB High-Speed (HS) signal conditioner designed to compensate for ISI signal loss in a transmission channel. TUSB211A has a patented design for USB Low Speed (LS) and Full Speed (FS) signals. It does not alter the signal characteristics. HS signals are compensated. The design is compatible with USB On-The-Go (OTG) and Battery Charging (BC) specifications.

Programmable signal gain through an external resistor permits fine tuning device performance to optimize signals. This helps pass USB HS electrical compliance tests at the connector. The TUSB211A allows application in series to cover longer distances, or high loss transmission paths. A maximum of 4 devices can be daisy-chained.

7.2 Functional Block Diagram



Copyright © 2018, Texas Instruments Incorporated

7.3 Feature Description

7.3.1 High-Speed EQ

The high-speed EQ (combination of edge boost and DC boost) improves the eye width for USB2.0 high-speed signals. It is direction independent and by that is compatible to OTG systems. The EQ pin is configuring the EQ strength with different values of pull down resistors to set 4 levels of EQ.

7.4 Device Functional Modes

7.4.1 Low-Speed (LS) Mode

TUSB211A automatically detects an LS connection and does not enable signal compensation. CD pin is asserted high but ENA_HS will be low.

7.4.2 Full-Speed (FS) Mode

TUSB211A automatically detects an FS connection and does not enable signal compensation. CD pin is asserted high but ENA HS will be low.

7.4.3 High-Speed (HS) Mode

TUSB211A automatically detects an HS connection and will enable signal compensation as determined by the external pull down resistance on its EQ pin.

CD pin and ENA HS pin are asserted high when high-speed EQ is active.

7.4.4 High-Speed Downstream Port Electrical Compliance Test Mode

TUSB211A will detect an HS compliance test fixture and enter the downstream port high-speed eye diagram test mode. CD pin will be low and ENA_HS pin is asserted high when TUSB211A is in HS eye compliance test mode.

If the RSTN pin is asserted low and de-asserted high while TUSB211A is operating in HS functional mode, then TUSB211A will transition to HS eye compliance test mode, the CD asserts low, and ENA_HS remains high. When all this occurs, signal compensation is enabled.



7.4.5 Shutdown Mode

TUSB211A can be disabled when its RSTN pin is asserted low. DP, DM traces are continuous through the device in shutdown mode. The USB channel is still fully operational, but there is neither signal compensation, nor any indication from the CD pin as to the status of the channel.

表 7-1. CD and ENA_HS Pins in Different Modes

MODE	CD	ENA_HS
Low-speed	HIGH	LOW
Full-speed	HIGH	LOW
High-speed	HIGH	HIGH
High-speed downstream port electrical test	LOW	HIGH
Shutdown	LOW	LOW



8 Application and Implementation

备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

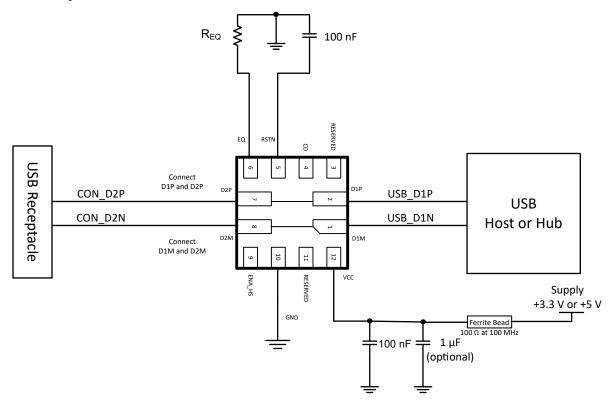
8.1 Application Information

The purpose of the TUSB211A is to restore the signal integrity of a USB High-speed channel up to the USB connector. The loss in signal quality stems from reduced channel bandwidth due to high loss PCB trace and other components that contribute a capacitive load. This can cause the channel to fail the USB near end eye mask. Proper use of the TUSB211A can help to pass this eye mask.

A secondary purpose is to use the CD pin of the TUSB211A to control other blocks on the customer platform, if so desired.

8.2 Typical Application

A typical application for TUSB211A is shown in 🛭 8-1. In this setup, D2P and D2M face the USB connector while D1P and D1M face the USB host. The orientation may be reversed [that is, D2 faces transceiver and D1 faces connector].



Copyright © 2023, Texas Instruments Incorporated

图 8-1. TUSB211A Reference Schematic

8.2.1 Design Requirements

TUSB211A requires a valid reset signal as described in the *Power Supply Recommendations* section. The capacitor at RSTN pin is not required if a micro controller drives the RSTN pin according to recommendations.

For this design example, use the parameters provided in 表 8-1.

表 8-1. Design Parameters for 3.3-V Supply With Low to Medium Loss System

PARAMETER							
V _{CC}							
I ² C support required in system (Yes/No)			No				
Edge and DC Boost	R _{EQ}	EQ Level					
	0- Ω	0					
	1.8 kΩ ±1%	1	EQ Level 0: R _{EQ} = 0- Ω				
	3.6 kΩ ±1%	2					
	Do Not Install (DNI)	3					

⁽¹⁾ These parameters are starting values for a low to medium loss system. Further tuning might be required based on specific host or device as well as cable length and loss profile. These settings are not specific to a 3.3-V supply system and could be applicable to 5-V supply system as well.

8.2.2 Detailed Design Procedure

The ideal EQ setting is dependent upon the signal chain loss characteristics of the target platform. The recommendation is to start with EQ Level 0, and then increment to EQ Level 1, and so on.

For the TUSB211A to recognize any change to the EQ setting, the RSTN pin must be toggled. This is because the EQ pin is latched on power up and the pin is ignored thereafter.

Placement of the device is also dependent on the application goal. 表 8-2 describes TI recommendations.

表 8-2. Platform Placement Guideline

PLATFORM GOAL	SUGGESTED TUSB211A PLACEMENT
Pass USB Near End Mask at the receptacle	Close to measurement point (connector)
Pass USB Far End Eye Mask at the plug	Close to USB PHY
Cascade multiple TUSB211As to improve device enumeration	Midway between each USB interconnect

表 8-3. Table of Recommended Settings

the or it is a second of the original of the original or it is a second or it is a s	90					
EQ settings ⁽¹⁾ for channel loss						
Pre-channel cable length (Between USB PHY and TUSB211A)	EQ					
0-3 meter	Level 0					
2-5 meter	Level 1					
Post-channel cable length (Between TUSB211A and inter-connect)	EQ					
0-2 meter	Level 0					
1-4 meter	Level 1					

(1) These parameters are starting values for different cable lengths. Further tuning might be required based on specific host or device as well as cable length and loss profile.

Product Folder Links: TUSB211A



8.2.2.1 Test Procedure to Construct USB High-Speed Eye Diagram

备注

USB-IF certification tests for High-speed eye masks require the *mandated use* of the USB-IF developed test fixtures. These test fixtures do not require the use of oscilloscope probes. Instead they use SMA cables. More information can be found at the USB-IF Compliance Updates Page. It is located under the *Electrical Specifications* section, ID 86 dated March 2013.

The following procedure must be followed before using any oscilloscope compliance software to construct a USB High-speed Eye Mask:

8.2.2.1.1 For a Host Side Application

- 1. Configure the TUSB211A to the desired EQ setting.
- 2. Power on (or toggle the RSTN pin if already powered on) the TUSB211A.
- 3. Using SMA cables, connect the oscilloscope and the USB-IF host-side test fixture to the TUSB211A.
- 4. Enable the host to transmit USB TEST PACKET.
- 5. Execute the oscilloscope USB compliance software.
- Repeat the above steps to re-test TUSB211A with a different EQ setting (must reset to change).

8.2.2.1.2 For a Device Side Application

- 1. Configure the TUSB211A to the desired EQ setting.
- 2. Power on (or toggle the RSTN pin if already powered on) the TUSB211A.
- 3. Connect a USB host, the USB-IF device-side test fixture, and USB device to the TUSB211A. Ensure that the USB-IF device test fixture is configured to the 'INIT' position.
- 4. Allow the host to enumerate the device.
- 5. Enable the device to transmit USB TEST PACKET.
- 6. Using SMA cables, connect the oscilloscope to the USB-IF device-side test fixture and ensure that the device-side test fixture is configured to the 'TEST' position.
- 7. Execute the oscilloscope USB compliance software.
- 8. Repeat the above steps to re-test TUSB211A with a different EQ setting (must reset to change).



8.2.3 Application Curves

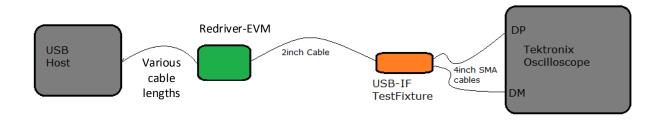
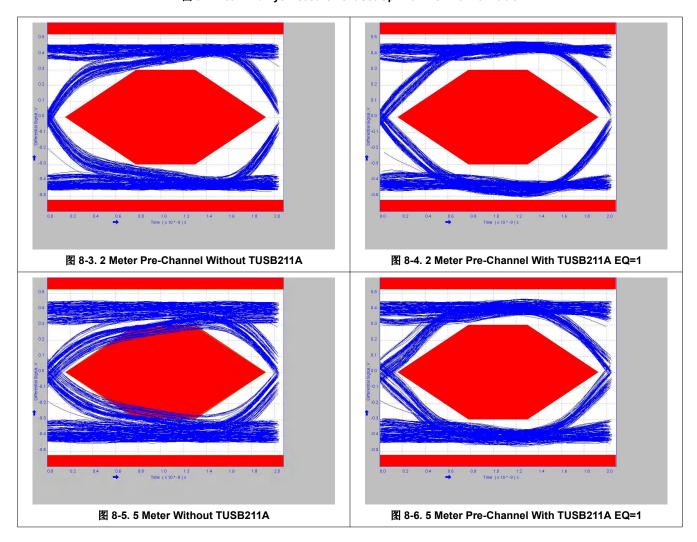
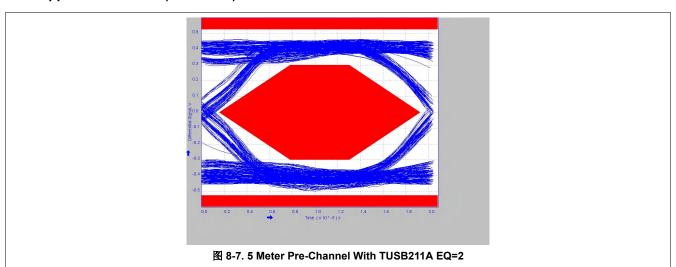


图 8-2. Near End Eye Measurement Set-Up With Pre-Channel Cable



English Data Sheet: SLLSFW2

8.2.3 Application Curves (continued)





8.2.3 Application Curves

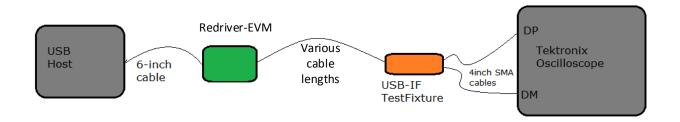
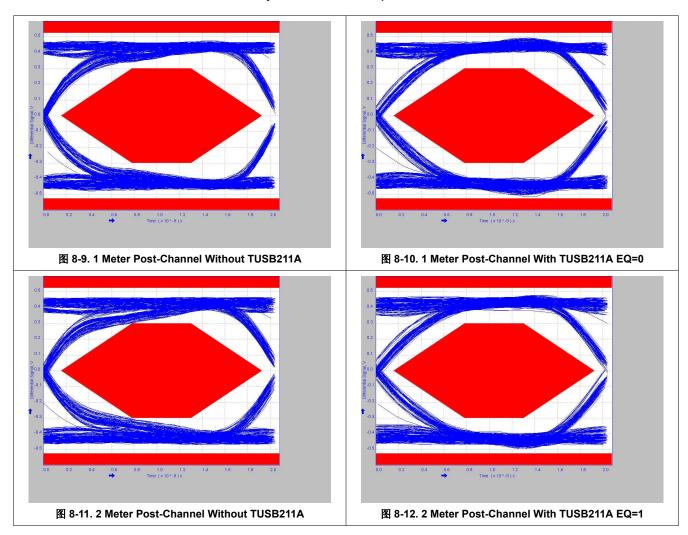
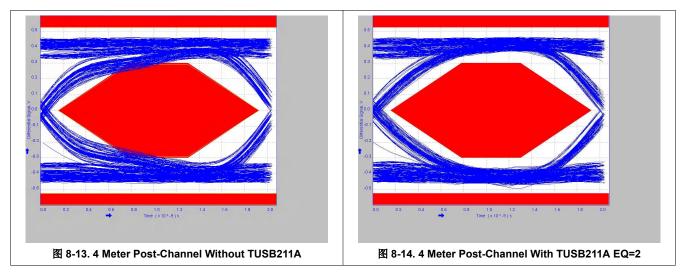


图 8-8. Near End Eye Measurement Set-Up With Post-Channel Cable



8.2.3 Application Curves (continued)



8.3 Power Supply Recommendations

On power up, the interaction of the RSTN pin and power on ramp could result in digital circuits not being set correctly. The device should not be enabled until the power on ramp has settled to the minimum recommended supply voltage or higher for a correct power on reset of the digital circuitry. If RSTN cannot be held low by microcontroller or other circuitry until the power on ramp has settled, then an external capacitor from the RSTN pin to GND is required to hold the device in the low power reset state.

The RC time constant should be larger than five times of the power on ramp time (0 to V_{CC}). With a typical internal pullup resistance of 500 k Ω , the recommended minimum external capacitance is calculated as:

$$[Ramp\ Time \times 5] \div [500\ k\Omega]$$
 (1)

8.4 Layout

8.4.1 Layout Guidelines

Although the land pattern has matched trace width to pad width, optimal impedance control is based on the user's own PCB stack-up. The recommendation is to maintain 90 Ω differential routing underneath the device.

Product Folder Links: TUSB211A



8.4.2 Layout Example

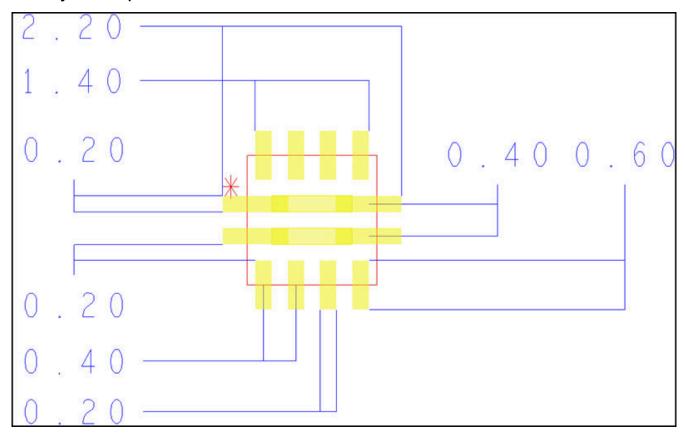


图 8-15. DP and DM Routing Underneath Device Package

English Data Sheet: SLLSFW2



9 Device and Documentation Support

9.1 接收文档更新通知

要接收文档更新通知,请导航至 ti.com 上的器件产品文件夹。点击*订阅更新* 进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

9.2 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料,可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者"按原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的《使用条款》。

9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

所有商标均为其各自所有者的财产。

9.4 静电放电警告



静电放电 (ESD) 会损坏这个集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理和安装程序,可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级,大至整个器件故障。精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

9.5 术语表

TI术语表本术语表列出并解释了术语、首字母缩略词和定义。

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Copyright © 2023 Texas Instruments Incorporated

Submit Document Feedback

www.ti.com 9-Nov-2025

PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
TUSB211AIRWBR	Active	Production	X2QFN (RWB) 12	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	1A
TUSB211AIRWBR.A	Active	Production	X2QFN (RWB) 12	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	1A
TUSB211ARWBR	Active	Production	X2QFN (RWB) 12	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	0 to 70	1A
TUSB211ARWBR.A	Active	Production	X2QFN (RWB) 12	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	0 to 70	1A

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents Tl's knowledge and belief as of the date that it is provided. Tl bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. Tl has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. Tl and Tl suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TUSB211A:

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

www.ti.com 9-Nov-2025

• Automotive : TUSB211A-Q1

NOTE: Qualified Version Definitions:

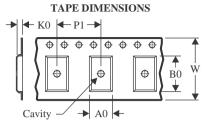
• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TUSB211AIRWBR	X2QFN	RWB	12	3000	180.0	9.5	1.8	1.8	0.45	4.0	8.0	Q1
TUSB211ARWBR	X2QFN	RWB	12	3000	180.0	9.5	1.8	1.8	0.45	4.0	8.0	Q1

www.ti.com 25-Sep-2024

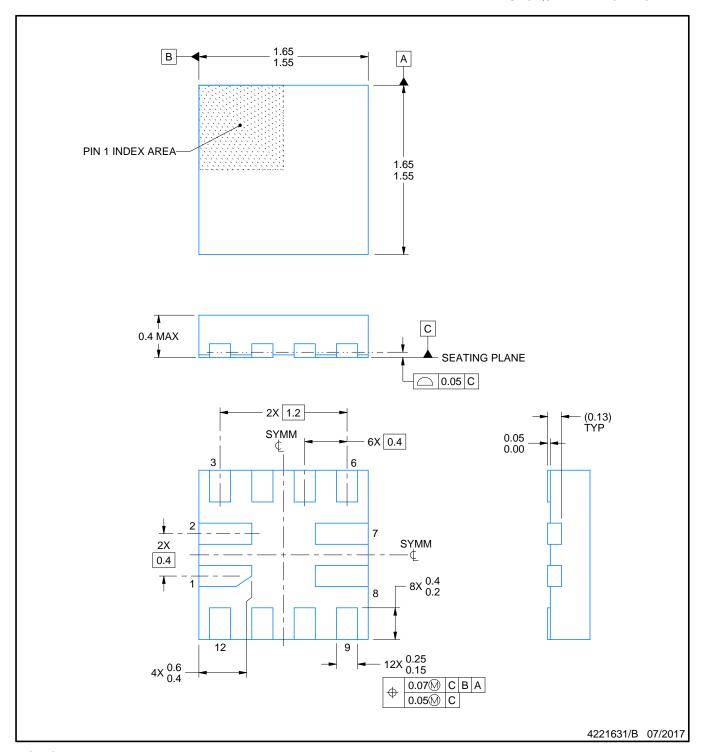


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TUSB211AIRWBR	X2QFN	RWB	12	3000	189.0	185.0	36.0
TUSB211ARWBR	X2QFN	RWB	12	3000	189.0	185.0	36.0



PLASTIC QUAD FLATPACK - NO LEAD



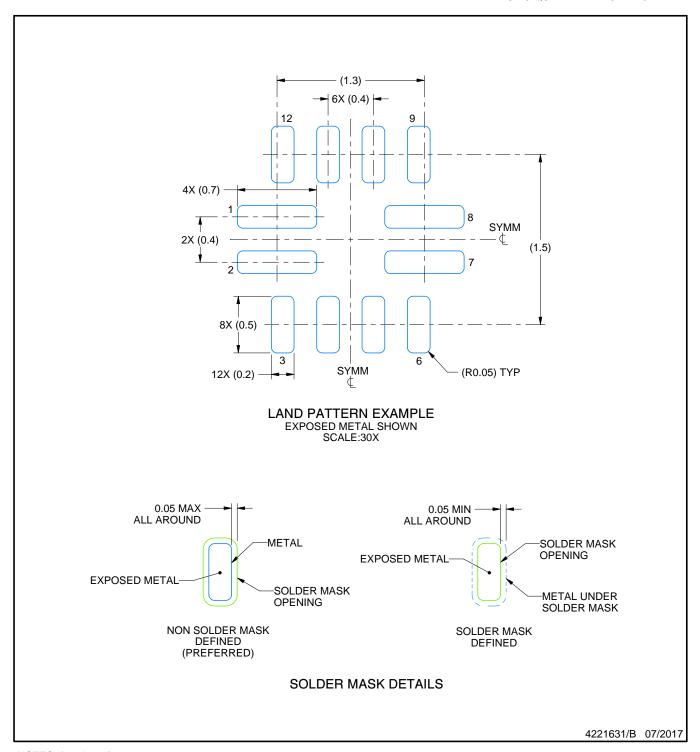
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.



PLASTIC QUAD FLATPACK - NO LEAD

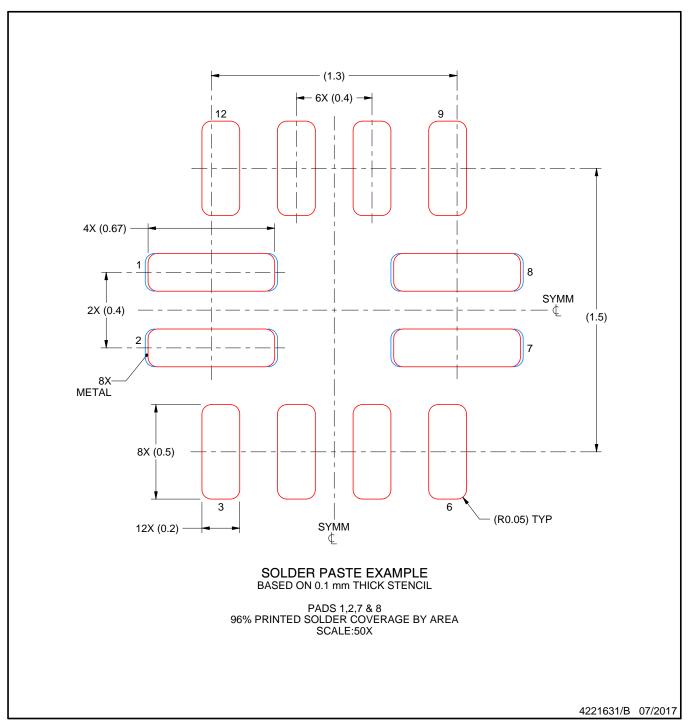


NOTES: (continued)

3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



重要通知和免责声明

TI"按原样"提供技术和可靠性数据(包括数据表)、设计资源(包括参考设计)、应用或其他设计建议、网络工具、安全信息和其他资源,不保证没有瑕疵且不做出任何明示或暗示的担保,包括但不限于对适销性、与某特定用途的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任:(1) 针对您的应用选择合适的 TI 产品,(2) 设计、验证并测试您的应用,(3) 确保您的应用满足相应标准以及任何其他安全、安保法规或其他要求。

这些资源如有变更,恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的相关应用。严禁以其他方式对这些资源进行复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。对于因您对这些资源的使用而对 TI 及其代表造成的任何索赔、损害、成本、损失和债务,您将全额赔偿,TI 对此概不负责。

TI 提供的产品受 TI 销售条款)、TI 通用质量指南 或 ti.com 上其他适用条款或 TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。 除非德州仪器 (TI) 明确将某产品指定为定制产品或客户特定产品,否则其产品均为按确定价格收入目录的标准通用器件。

TI 反对并拒绝您可能提出的任何其他或不同的条款。

版权所有 © 2025, 德州仪器 (TI) 公司

最后更新日期: 2025 年 10 月